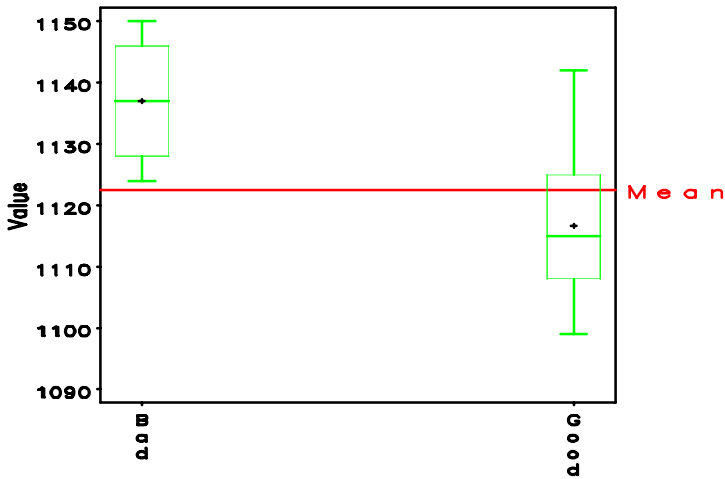


Split Analysis on Process Data

Event/Parameter: **_P220K14E12/TMWV_1W1R**
product F2TP2C3P

F_test=7.22 and P(F>f)=0.0198



SPLIT

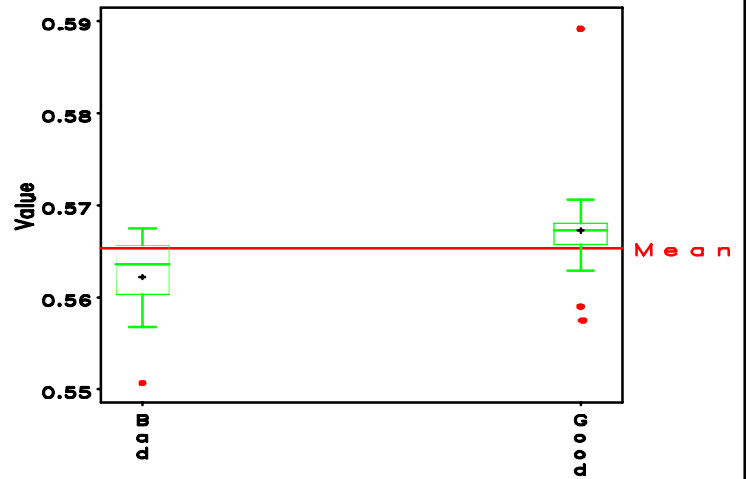
Good: high yield lots; Bad: low yield lots

Jeff Y. on 18NOV08

Split Analysis on Process Data

Event/Parameter: **_GETCD5L4280/CDMEAN**
product F2TP2C3P

F_test=6.06 and P(F>f)=0.0198



SPLIT

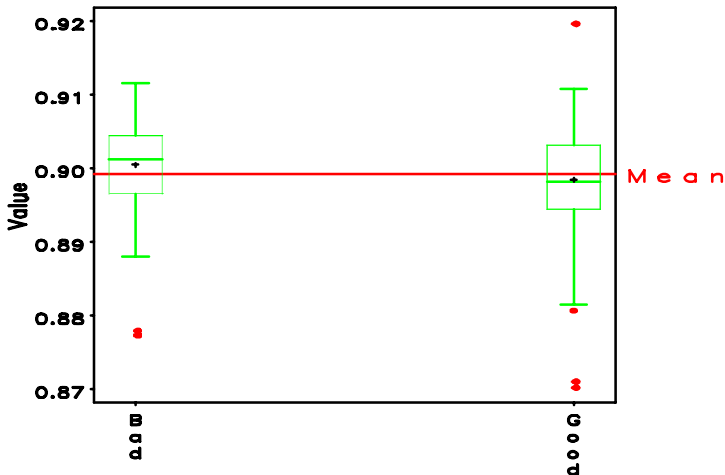
Good: high yield lots; Bad: low yield lots

Jeff Y. on 18NOV08

Split Analysis on Process Data

Event/Parameter: **_CDHC52800_/RATIO10_**
product F2TP2C3P

F_test=6.51 and P(F>f)=0.0112



SPLIT

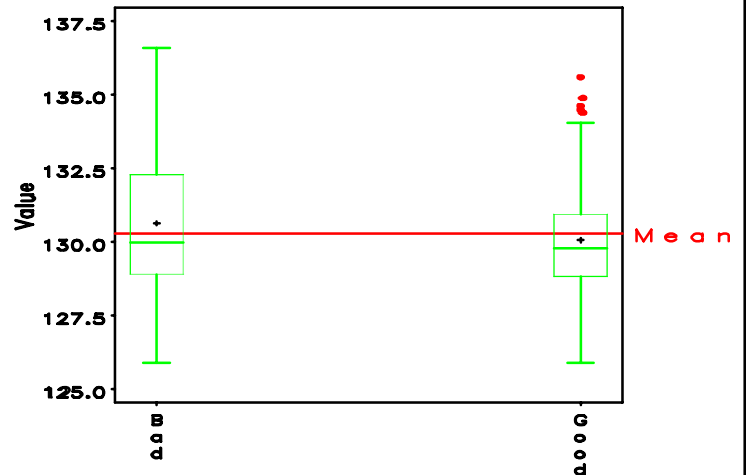
Good: high yield lots; Bad: low yield lots

Jeff Y. on 18NOV08

Split Analysis on Process Data

Event/Parameter: **_PADOX130/THK_2W5R**
product F2TP2C3P

F_test=5.91 and P(F>f)=0.0157



SPLIT

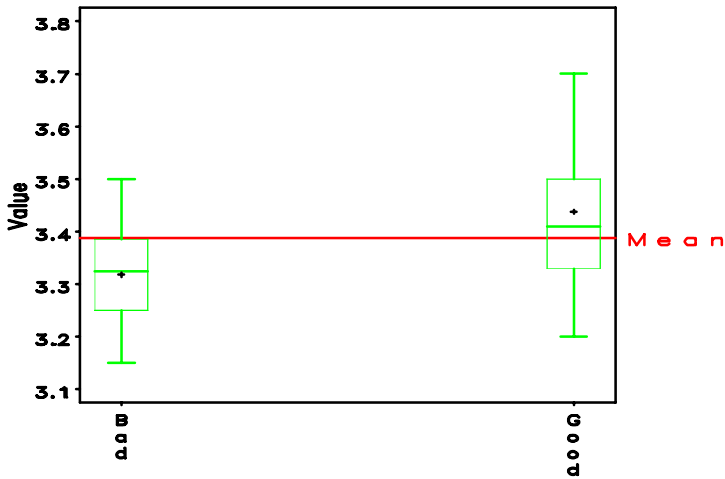
Good: high yield lots; Bad: low yield lots

Jeff Y. on 18NOV08

Split Analysis on Process Data

Event/Parameter: **_PMD-1/POLISH_TIME**
product F2TP2C3P

F_test=5.74 and P(F>f)=0.0237



SPLIT

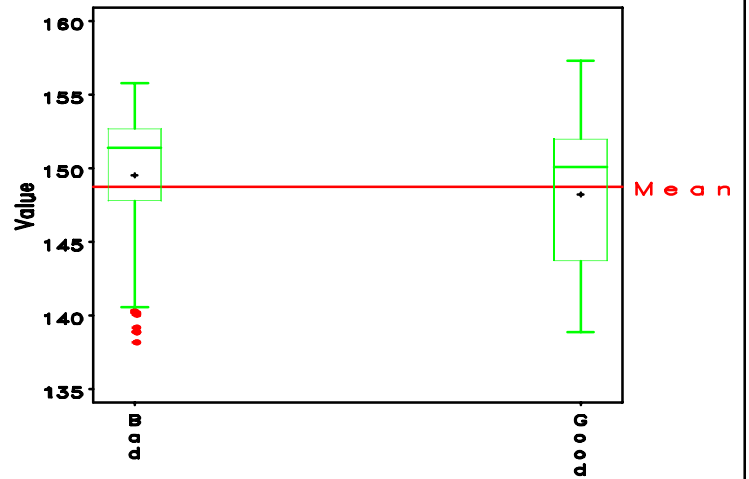
Good: high yield lots; Bad: low yield lots

Jeff Y. on 18NOV08

Split Analysis on Process Data

Event/Parameter: **_STRGATE150/THK_2W5R**
product F2TP2C3P

F_test=5.03 and P(F>f)=0.0257



SPLIT

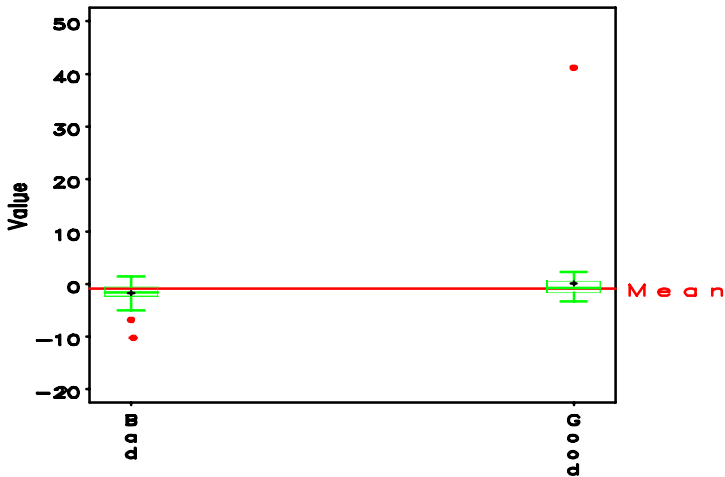
Good: high yield lots; Bad: low yield lots

Jeff Y. on 18NOV08

Split Analysis on Process Data

Event/Parameter: **_CDHC52800/_DERVCD10_**
product F2TP2C3P

F_test=5.85 and P(F>f)=0.019



SPLIT

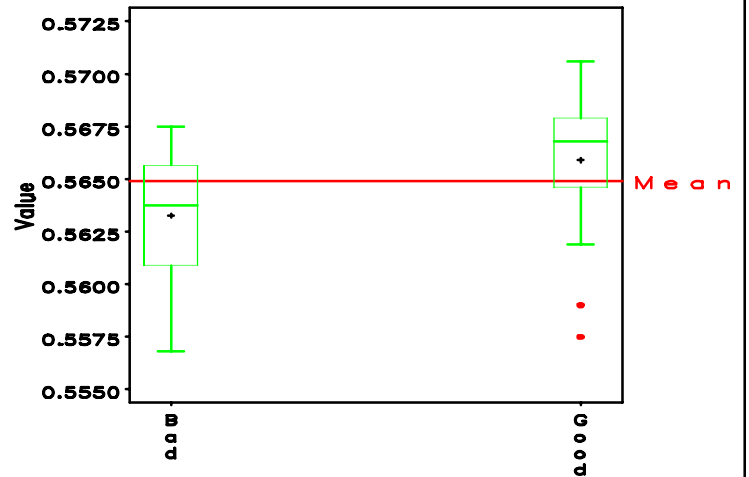
Good: high yield lots; Bad: low yield lots

Jeff Y. on 18NOV08

Split Analysis on Process Data

Event/Parameter: **_E_HCM5_2890/PRE**
product F2TP2C3P

F_test=4.92 and P(F>f)=0.0342



SPLIT

Good: high yield lots; Bad: low yield lots

Jeff Y. on 18NOV08